App. Serial No. 10/598,755 Docket No.: NL040276US1

In the Specification:

Please amend paragraph 0010 of the Specification as follows:

[0010] In another preferred embodiment of a method according to the invention, the first and second implantations (I_1 , I_2) are annealed at a temperature between 500 [[en]] and 700 degrees Celsius. In this way, both the horizontal and the vertical part of the pnjunction are formed by solid phase epitaxial regrowth. This greatly contributes to the shallowness and steepness of the pn-junction formed, which in turn is essential for future C-MOS technology.